

14. TEST SETUP PHOTOGRAPHS

FCC ID: ZNFVS995		HAC (T-COIL) TEST REPORT		Reviewed by: Quality Manager
Filename: 0Y1607051224-R2.ZNF	Test Dates: 07/08/2016 - 07/15/2016	DUT Type: Portable Handset		Page 69 of 71

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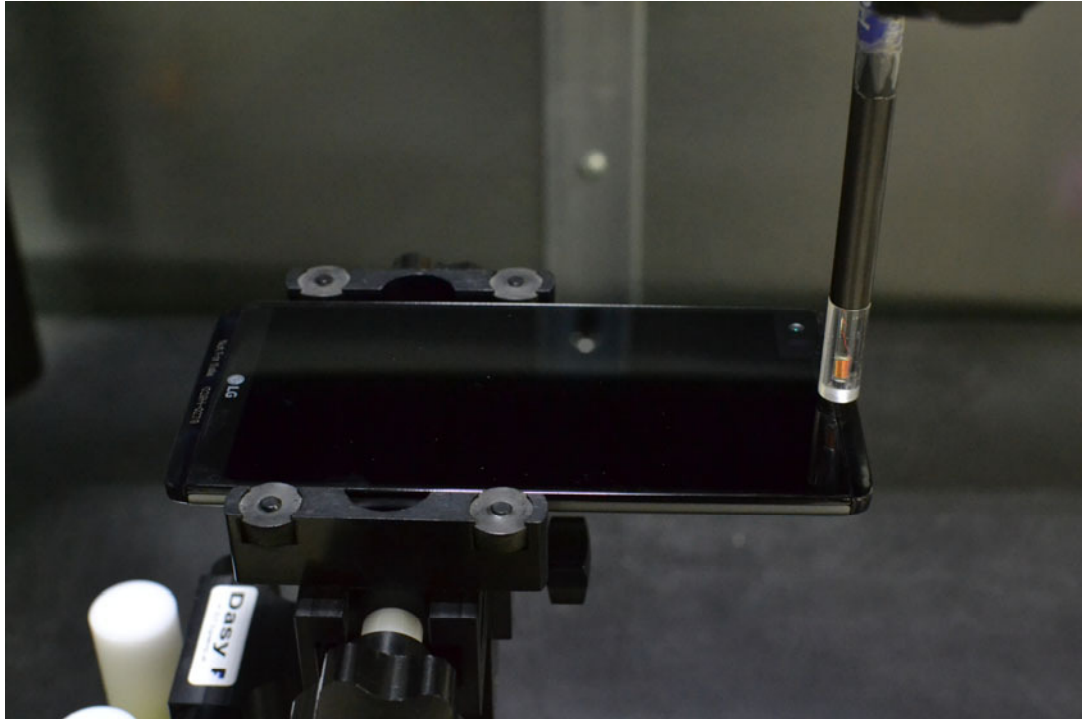


Figure 14-1
Test Setup for Wireless Device

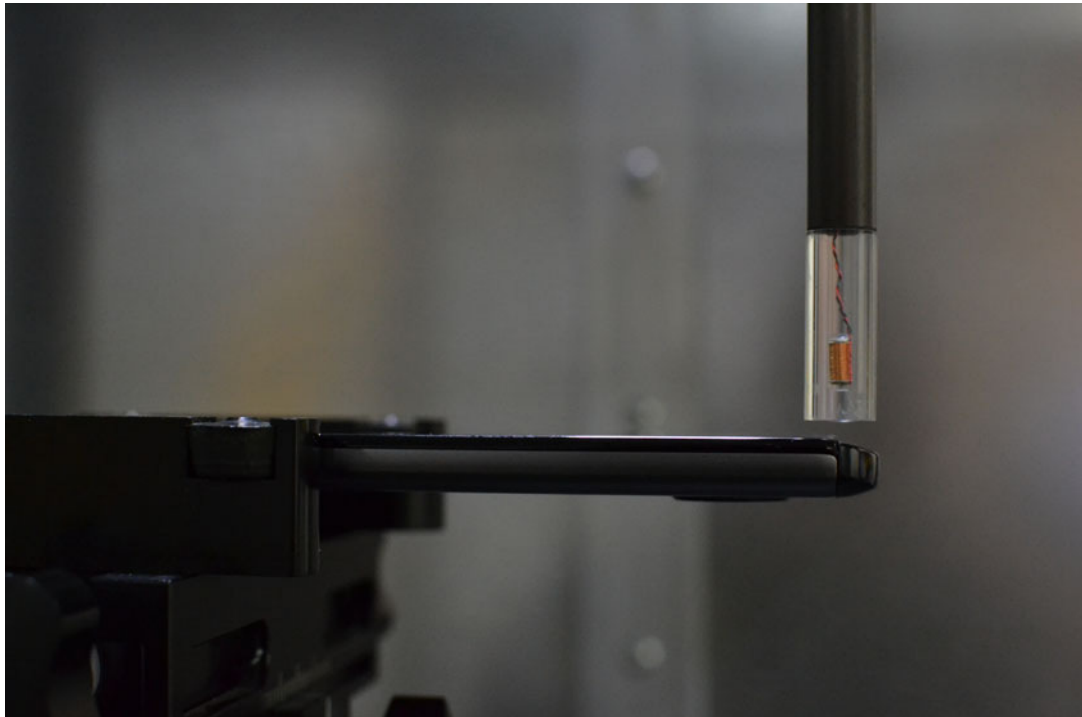


Figure 14-2
Test Setup for Wireless Device

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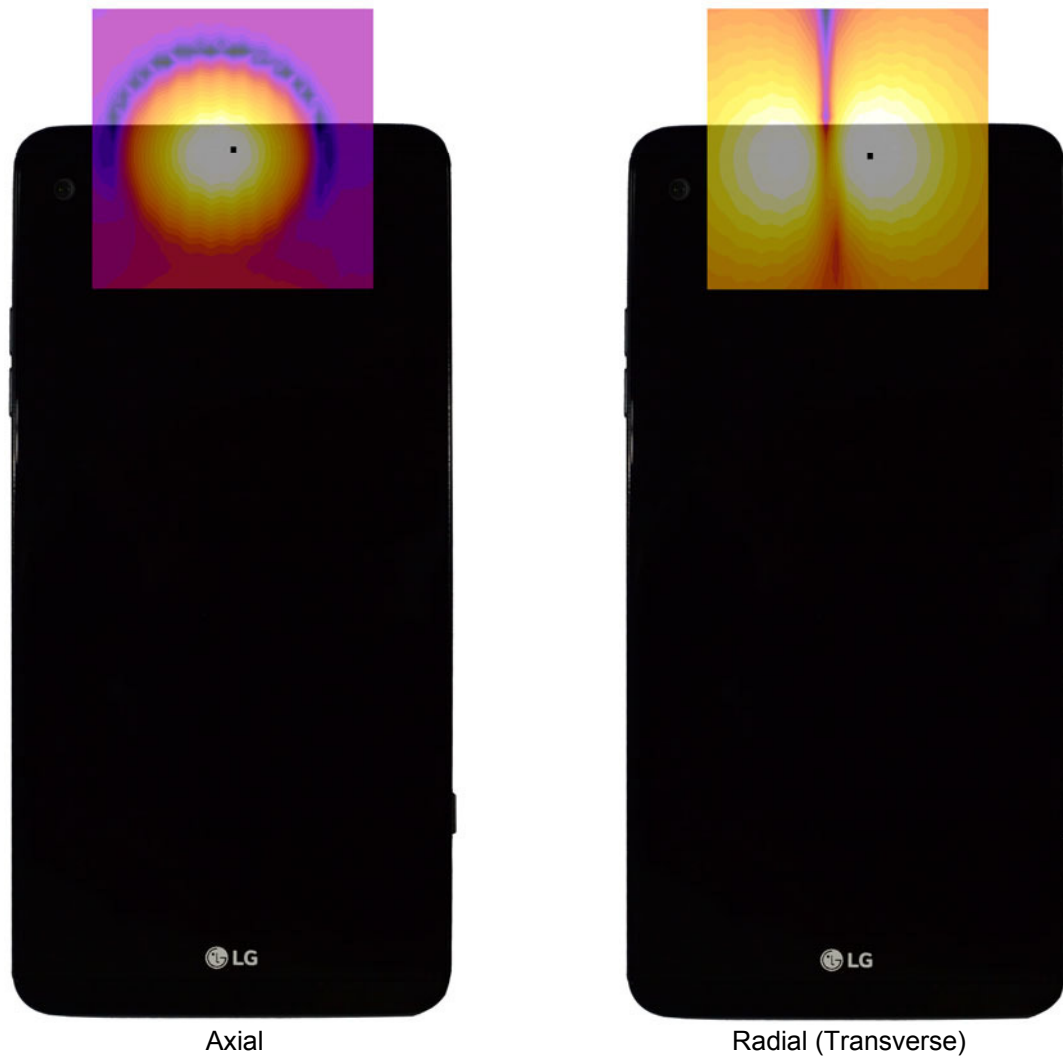


Figure 14-3
T-Coil Scan Overlay Magnetic Field Distributions

Note: Final measurement locations are indicated by a cursor on the contour plots.

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